

Wim Coene received the PhD degree in physics from the University of Antwerp in 1986, for his research on computational modeling of high-energy electron diffraction and image formation in a high-resolution transmission electron microscope (TEM). He joined the Philips Research Laboratories in Eindhoven in 1988, where he worked on phase-retrieval methods in high-resolution TEM devised for digital correction of electron-optical aberrations. In 1996, he started to work on channel coding and signal processing for optical storage; this research was directed on Blu-Ray disc technology, and on future generations of optical storage like near-field recording and 2D optical storage. He joined ASML Netherlands B.V. in Veldhoven in 2007, where he is currently Director of Research. Since 2015, he is also part-time Professor at the Optics group of the Delft University of Technology. In the recent years of his combined assignment at TU-Delft and ASML, his scientific interests have been focused on optical metrology for nanolithography in the semiconductor industry, with a focus on computational imaging, inverse problems and phase retrieval. In 2017-2018, he has initiated and shaped a NWO-TTW Perspective Program with 5 academic groups in the Netherlands, on *Lensless Imaging of 3D Nanostructures with Soft X-Rays* (LINX). Within this LINX Program, an EUV beamline has been designed and constructed at TU-Delft, for which the algorithmic concept of lensless imaging has been developed in order to image nanostructures in future generation of chips from a number of far-field diffraction patterns.